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PCN# : P2B7A
Issue Date : Jan. 22, 2013

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples. Alternatively, you may send an email request for data, samples or other information to PCNSupport@fairchildsemi.com.

Implementation of change:

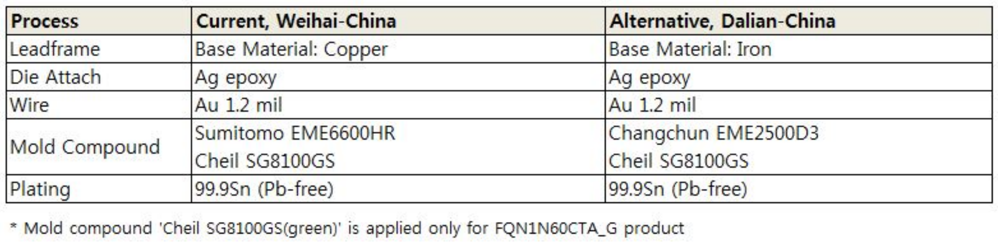
Expected First Shipment Date for Changed Product : Apr. 22, 2013

Expected First Date Code of Changed Product :1308

Description of Change (From) :
Current assembly and test location of TO92HP at Weihai, China

Description of Change (To) :
Alternate assembly and test location at Dalian, China

Reason for Change:
To provide alternative manufacturing site for TO92HP package for capacity increase.



Process	Current, Weihai-China	Alternative, Dalian-China
Leadframe	Base Material: Copper	Base Material: Iron
Die Attach	Ag epoxy	Ag epoxy
Wire	Au 1.2 mil	Au 1.2 mil
Mold Compound	Sumitomo EME6600HR Cheil SG8100GS	Changchun EME2500D3 Cheil SG8100GS
Plating	99.9Sn (Pb-free)	99.9Sn (Pb-free)

* Mold compound 'Cheil SG8100GS(green)' is applied only for FQN1N60CTA_G product

Affected Product(s):

FQN1N50CTA	FQN1N60CTA	FQN1N60CTA_G

Qualification Plan	Device	Package	Process	No. of Lots
Q20110475	FQN1N60CTA	TO-92HP	CFET	3

Test Description:	Condition:	Standard :	Duration:	Results:
High Temperature Gate Bias	145C, 30V	JESD22-A108	168 , 500 , 1000 hrs	0/237
High Temperature Reverse Bias	145C, 480V	JESD22-A108	168 , 500 , 1000 hrs	0/237
High Temperature Storage Life	145C	JESD22-A103	168 , 500 , 1000 hrs	0/237
Highly Accelerated Stress Test	130C, 85%RH, 42V	JESD22-A110	96 hrs	0/237
Temperature Cycle	-65C, 150C	JESD22-A104	100, 500 cycles	0/237